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MAY 26 2004



## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Seishiro Fujii et al. Art Unit : 1645  
 Serial No. : 10/664,795 Examiner : Unknown  
 Filed : September 19, 2003  
 Title : METHODS AND COMPOSITIONS FOR PREVENTING SKIN DAMAGE

Commissioner for Patents  
 P.O. Box 1450  
 Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Applicant submits the references listed on the attached form PTO-1449. A copy of a communication from a foreign patent office in a counterpart application is also enclosed.

This statement is being filed before the receipt of a first Office action on the merits.  
 Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: May 20, 2004



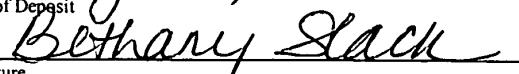
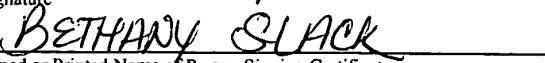
Leda Trivinos  
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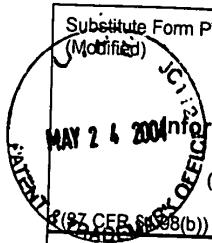
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## CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 10287-077001	Application No. 10/664,795		
 <p><b>Supplemental Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR 1.98(b))</p>		Applicant Seishiro Fujii et al.					
		Filing Date September 19, 2003		Group Art Unit 1645			
<b>U.S. Patent Documents</b>							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,299,858	10/09/2001	Serbedzija et al.			
	AB						

<b>Foreign Patent Documents or Published Foreign Patent Applications</b>							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes      No
	AC						
	AD						

<b>Other Documents (include Author, Title, Date, and Place of Publication)</b>							
Examiner Initial	Desig. ID	Document					
	AE						
	AF						

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	